[MOSFET](#) – Dual, P-Channel, POWERTRENCH®
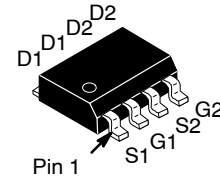
2.5 V Specified

FDS9933A

General Description

These P−Channel 2.5 V specified MOSFETs are produced using **onsemi**'s advanced POWERTRENCH process that has been especially tailored to minimize the on−state resistance and yet maintain low gate charge for superior switching performance.

Features

- −3.8 A, −20 V. $R_{DS(on)} = 0.075\ \Omega$, $V_{GS} = -4.5$ V
  $R_{DS(on)} = 0.105\ \Omega$, $V_{GS} = -2.5$ V
- Low Gate Charge (7 nC Typical)
- Fast Switching Speed
- High Performance Trench Technology for Extremely Low $R_{DS(on)}$
- High Power and Current Handling Capability
- This Device is Pb−Free and Halide Free

Applications

- Load Switch
- DC/DC Converters
- Motor Drives

SOIC8
CASE 751EB

MARKING DIAGRAM

FDS9933A
ALYW

FDS9933A = Device Code
A   = Assembly Site
L   = Wafer Lot Number
YW   = Assembly Start Week

PIN CONNECTIONS

ABSOLUTE MAXIMUM RATINGS ($T_A = 25°C$ unless otherwise noted)

Symbol	Parameter		Value	Unit
V_{DSS}	Drain−Source Voltage		−20	V
V_{GSS}	Gate−Source Voltage		±8	V
I_D	Drain Current	Continuous (Note 1a)	−3.8	A
		Pulsed	−20	
P_D	Power Dissipation for Dual Operation		2.0	W
	Power Dissipation for Single Operation (Note 1a) (Note 1b) (Note 1c)		1.6 1.0 0.9	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		−55 to 150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

ORDERING INFORMATION
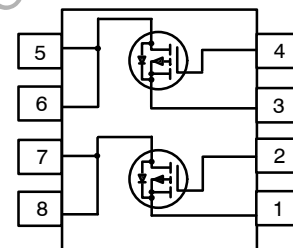
Device	Package	Shipping†
FDS9933A	SOIC8	2500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, [BRD8011/D](#).

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JA}$	Thermal Resistance, Junction−to−Ambient (Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction−to−Case (Note 1)	40	°C/W

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
BV_{DSS}	Drain−Source Breakdown Voltage	V_{GS} = 0 V, I_D = −250 µA	−20	−	−	V
$\dfrac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = −250 µA, Referenced to 25°C	−	−16	−	mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = −16 V, V_{GS} = 0 V	−	−	−1	µA
I_{GSSF}	Gate−Body Leakage, Forward	V_{GS} = 8 V, V_{DS} = 0 V	−	−	100	nA
I_{GSSR}	Gate−Body Leakage, Reverse	V_{GS} = −8 V, V_{DS} = 0 V	−	−	−100	nA
ON CHARACTERISTICS (Note 2)						
$V_{GS(TH)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = −250 µA	−0.4	−0.8	−1.5	V
$\dfrac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = −250 µA, Referenced to 25°C	−	2.5	−	mV/°C
$R_{DS(on)}$	Static Drain−Source On−Resistance	V_{GS} = −4.5 V, I_D = −3.8 A	−	0.058	0.075	Ω
		V_{GS} = −4.5 V, I_D = −3.8 A, T_J = 125°C	−	0.086	0.12	
		V_{GS} = −2.5 V, I_D = −3.3 A	−	0.084	0.105	
$I_{D(on)}$	On−State Drain Current	V_{GS} = −4.5 V, V_{DS} = −5.0 V	−10	−	−	A
g_{FS}	Forward Transconductance	V_{DS} = −4.5 V, I_D = −3.8 A	−	10	−	S
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = −10 V, V_{GS} = 0 V, f = 1.0 MHz	−	600	−	pF
C_{oss}	Output Capacitance		−	175	−	pF
C_{rss}	Reverse Transfer Capacitance		−	80	−	pF
SWITCHING CHARACTERISTICS (Note 2)						
$t_{d(on)}$	Turn−On Delay Time	V_{DD} = −5 V, I_D = −0.5 A, V_{GS} = −4.5 V, R_{GS} = 6.0 Ω	−	6	12	ns
t_r	Turn−On Rise Time		−	9	18	ns
$t_{d(off)}$	Turn−Off Delay Time		−	31	50	ns
t_f	Turn−Off Fall Time		−	28	42	ns
Q_g	Total Gate Charge	V_{DS} = −10 V, I_D = −3.8 A, V_{GS} = −4.5 V	−	7	10	nC
Q_{gs}	Gate−Source Charge		−	1.3	−	nC
Q_{gd}	Gate−Drain Charge		−	2	−	nC
DRAIN−SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS						
I_S	Maximum Continuous Drain−Source Diode Forward Current		−	−	−1.3	A
V_{SD}	Drain−Source Diode Forward Voltage	V_{GS} = 0 V, I_S = −1.3 A (Note 2)	−	−0.75	−1.2	V

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
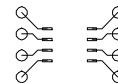
1. $R_{\theta JA}$ is the sum of the junction−to−case and case−to−ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta JA}$ is determined by the user's board design.
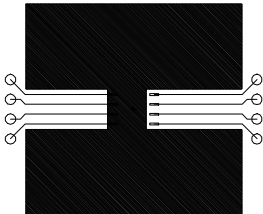
a) 78°C/W when mounted on a 0.5 in² pad of 2 oz. Copper
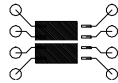
b) 125°C/W when mounted on a 0.02 in² pad of 2 oz. copper

c) 135°C/W when mounted on a 0.003 in² pad of 2 oz. copper.

2. Pulse Test Pulse Width ≤ 300 µs, Duty Cycle ≤ 2.0%
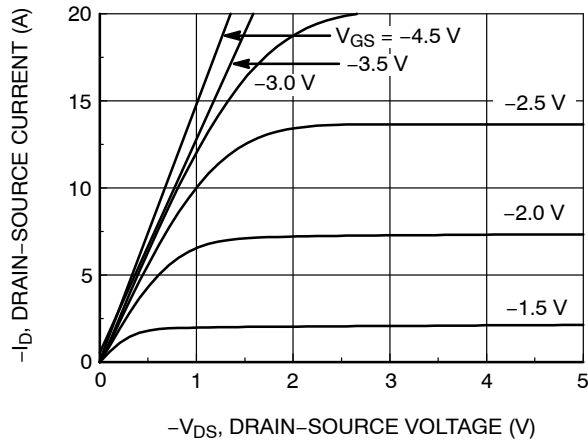
TYPICAL CHARACTERISTICS

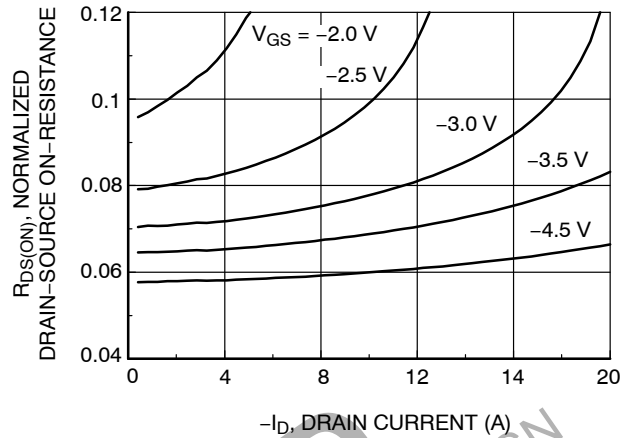**Figure 1. On−Region Characteristics**

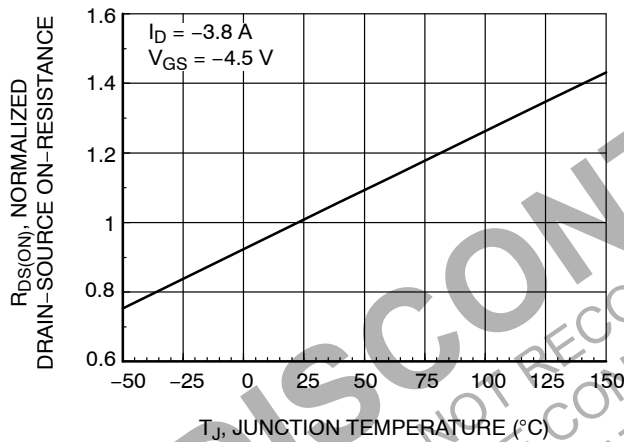**Figure 2. On−Resistance Variation with Drain Current and Gate Voltage**

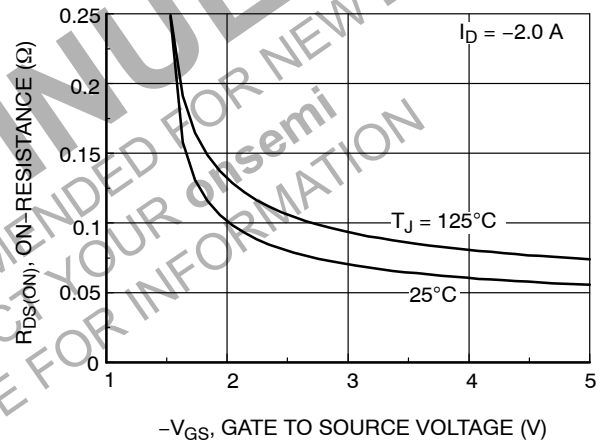**Figure 3. On−Resistance Variation with Temperature**

Figure 4. On−Resistance Variation with Gate−to−Source Voltage
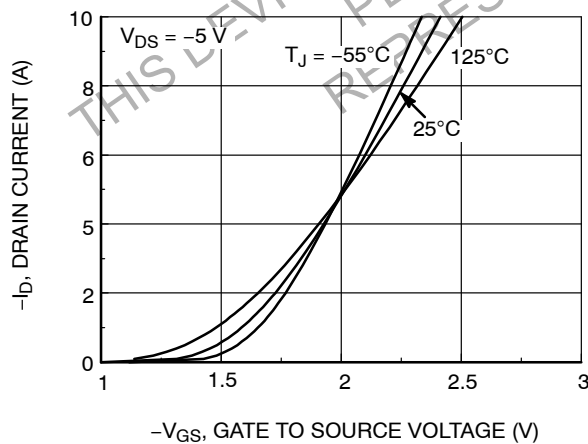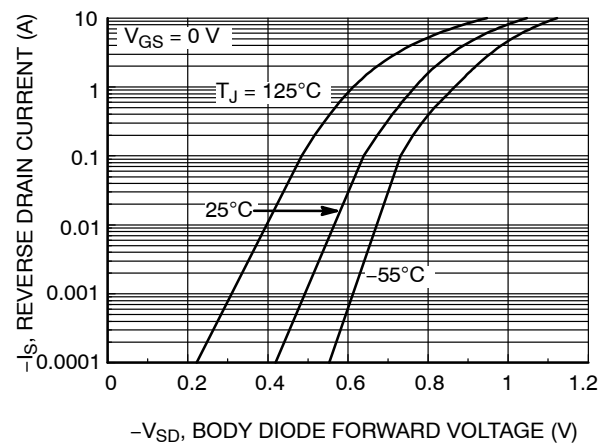

Figure 5. Transfer Characteristics

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature
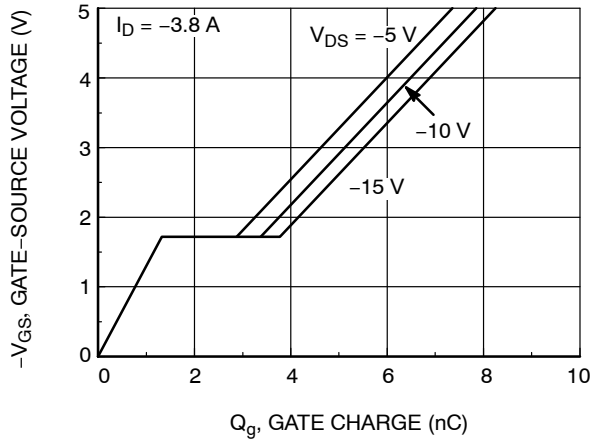
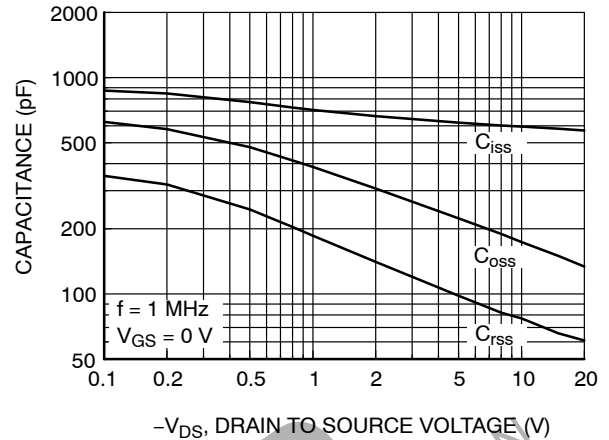## TYPICAL CHARACTERISTICS (continued)

Figure 7. Gate Charge Characteristics

Figure 8. Capacitance Characteristics
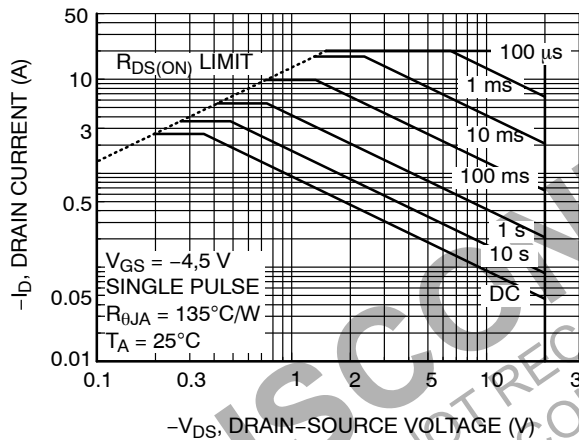
Figure 9. Maximum Safe Operating Area
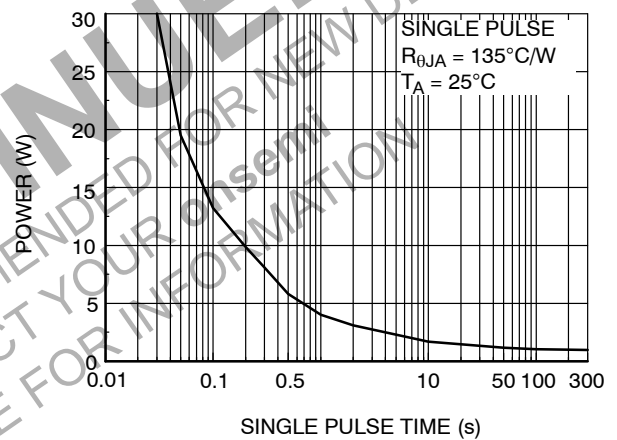
Figure 10. Single Pulse Maximum Power Dissipation
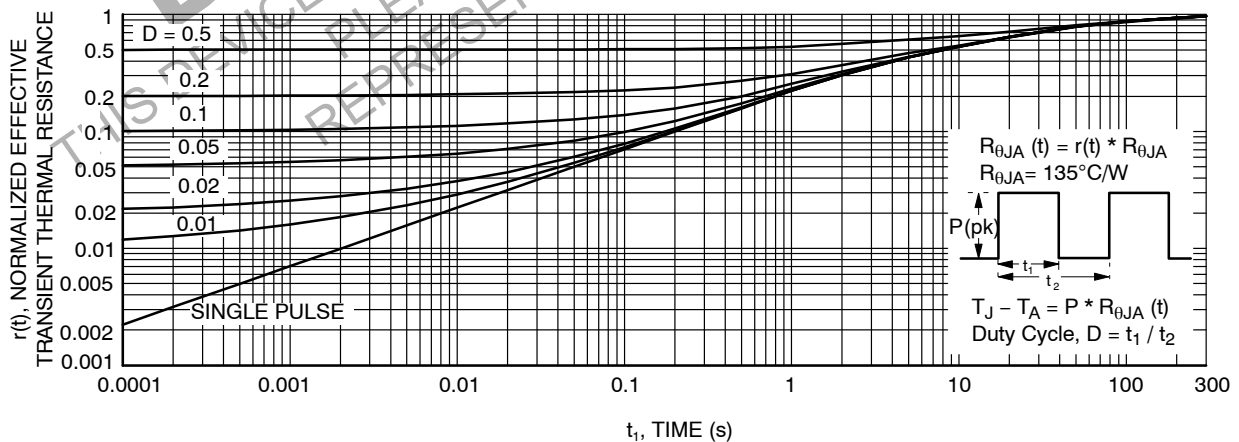
Figure 11. Transient Thermal Response Curve

Thermal characterization performed using the conditions described in Note 1c.
Transient thermal response will change depending on the circuit board design.

SOIC8
CASE 751EB
ISSUE A

DATE 24 AUG 2017

4.90±0.10 A

(0.635)

8   5   B

6.00±0.20   3.90±0.10

PIN ONE
INDICATOR

1   4

1.27

⊕ 0.25 (M) C B A

0.65

1.75

5.60

1.27

LAND PATTERN RECOMMENDATION

0.175±0.075

1.75 MAX   C

0.42±0.09

0.10

SEE DETAIL A

0.22±0.03

OPTION A - BEVEL EDGE

OPTION B - NO BEVEL EDGE

(0.43) x 45°

R0.10   GAGE PLANE

R0.10

0.25

8°
0°

SEATING PLANE

0.65±0.25

(1.04)

DETAIL A
SCALE: 2:1
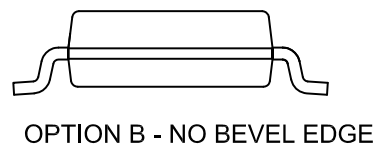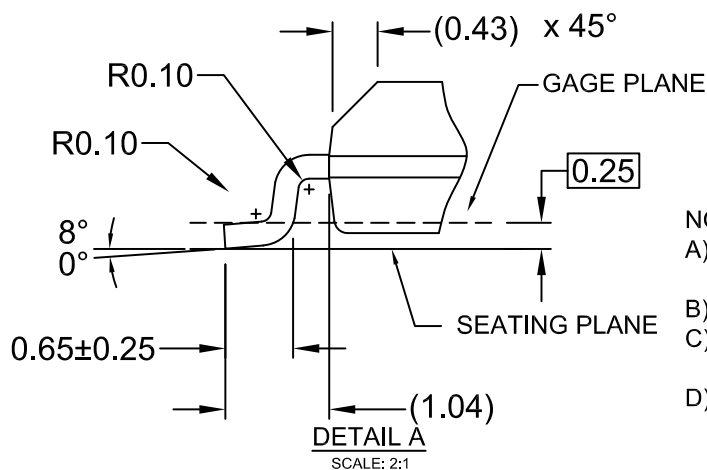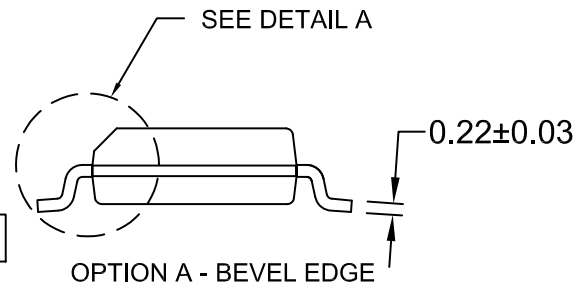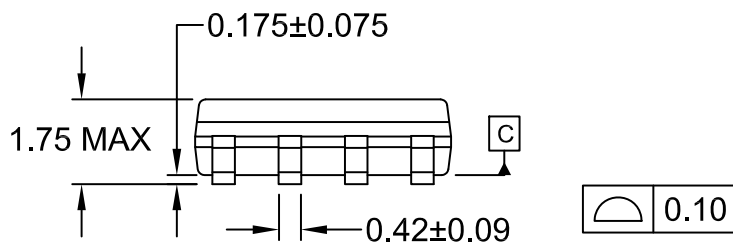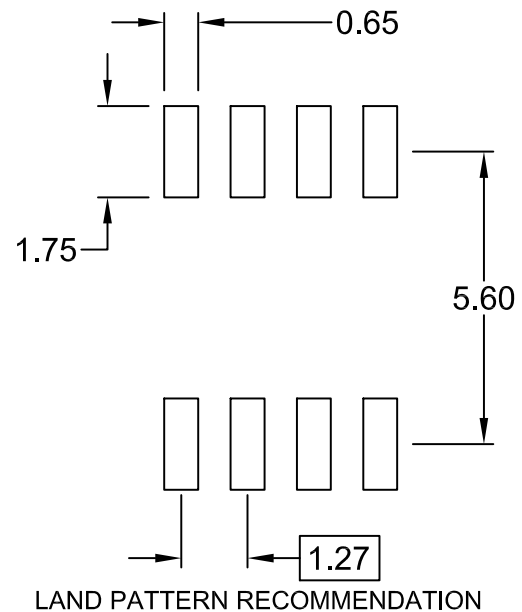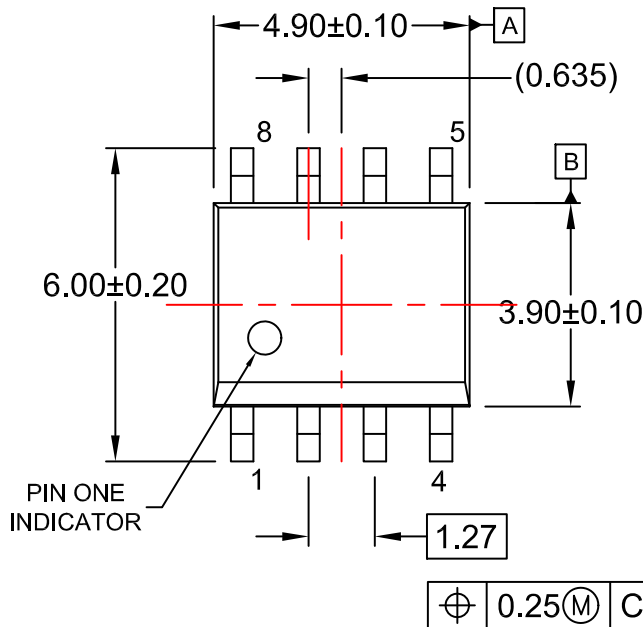
NOTES:
A) THIS PACKAGE CONFORMS TO JEDEC
    MS-012, VARIATION AA.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONS DO NOT INCLUDE MOLD
    FLASH OR BURRS.
D) LANDPATTERN STANDARD: SOIC127P600X175-8M

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